

#8/A  
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Robertson

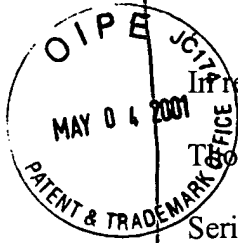
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003263.P003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In re Application of:

Thomson et al.

Serial No. 09/471,467

Filed: December 22, 1999

For: SCANNING FORCE MICROSCOPE  
PROBE CANTILEVER WITH  
REFLECTIVE STRUCTURE

Examiner: Daniel Larkin

Art Unit: 2856

Box Non-Fee Amendment  
Honorable Commissioner for Patents  
Washington, DC 20231

AMENDMENT AND RESPONSE

Sir:

Responsive to the Office Action mailed February 2, 2001, the Applicants request the Examiner to enter the following amendments and to consider the following remarks.

IN THE SPECIFICATION

Please replace the paragraph beginning at page 3, line 1, with the following rewritten paragraph:

--Another disadvantage with the present day scanning force microscope 101 is that it is difficult to measure simultaneously two or more nodes in close proximity on the surface 118 of sample 117. In particular, since mirror 111 is positioned above cantilever 115 and protrudes beyond the free end of cantilever 115 as shown in Figure 1, it is

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